

Notice of References CitedApplication/Case No.
09/977,994Applicant(s)/Patent Under
Reexamination
NAGATA ET AL.Examiner
Jeffrey R. WestArt Unit
2857

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,300,798	04-1994	Yamazaki et al.	257/207
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Nagata et al., "Measurements and Analyses of Substrate Noise Waveform in Mixed Signal IC Environment". Proceedings of the IEEE 1999 Custom Integrated Circuits Conference. May 1999.
	V	Shimazaki et al., "LEMMINGS: LSI's EMI-Noise Analysis With Gate Level Simulator". Proceedings of the IEEE 2000 First International Symposium on Quality Electronic Design. March 2000.
	W	Mitra et al., "Substrate-Aware Mixed-Signal Macrocell Placement in WRIGHT". IEEE Journal of Solid-State Circuits. Vol. 30. No. 3, March 1995.
	X	Su et al., "Experimental Results and Modeling Techniques for Substrate Noise in Mixed-Signal Integrated Circuits". IEEE Journal of Solid-State Circuits. Vol. 28. No. 4, April 1993.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.